

## Administrivia

- HW #5 changes
- HW #6
  - Will be up by tonight, 5 problems
  - Due next Wednesday (08/06)
  - Will be a good review for the midterm
- Return HWs 4 and 5 on Monday (08/04)
- Return HW 3 and corrected HWs 1 and 2 on Friday (08/01)
- Midterm II next Wednesday, 08/06/03!
- Practice problems up by tonight
- Review session?

**Last time...**

- CMOS voltage transfer characteristic
  - SUGGESTION: Go over lecture 16 STEP-BY-STEP
  - Ask questions in discussion and office hours!

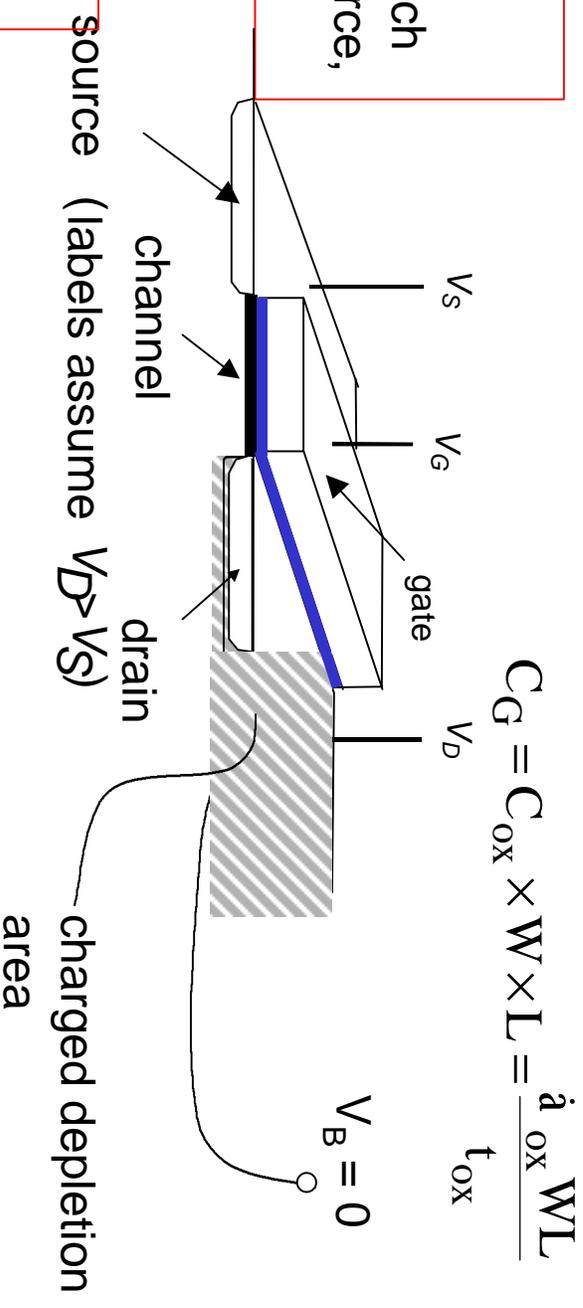
**This time...**

- CMOS inverter propagation delay analysis
  - Complete our propagation delay model
  - Understand MOS capacitances
  - Switch-RC model of the CMOS inverter
  - Understand  $\tau_{LH}$  and  $\tau_{HL}$
- CMOS layouts and fabrication steps
- Extract capacitances,  $W$  and  $L$  from layout/crosssection
- References: Lectures 18 and 19 (Fall 1999) and Lecture 21 (Spring 2003)

## MOSFET Capacitances

### Node connected to the gate:

Capacitance  $C_G$  is between gate and the underlying channel, which is connected to the source,  $C_{GS} = C_G$



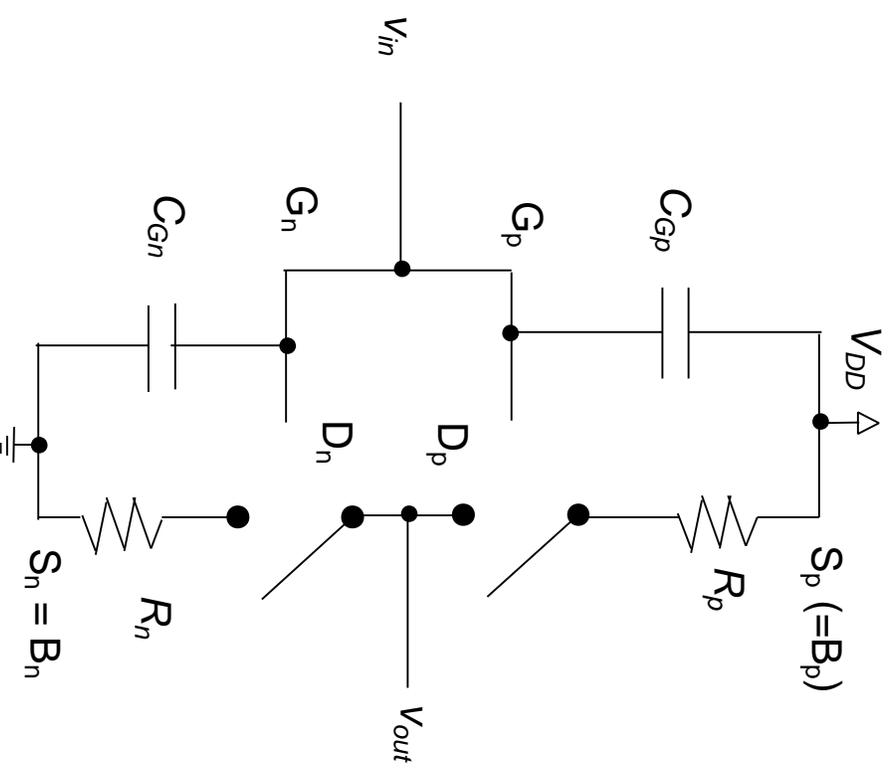
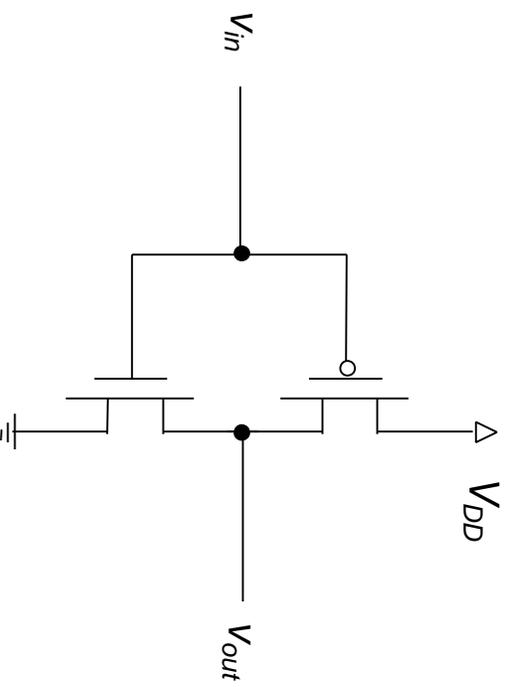
And  $C_{DB}$  is capacitance between drain electrode and body (bulk).

### Node connected to the drain (or source):

- pn junction capacitance between drain and bulk is  $C_{DB}$
- capacitance  $C_{SB}$  is shorted out since  $V_S = V_B$  in digital circuits

# The CMOS Inverter

## Symbolic circuit



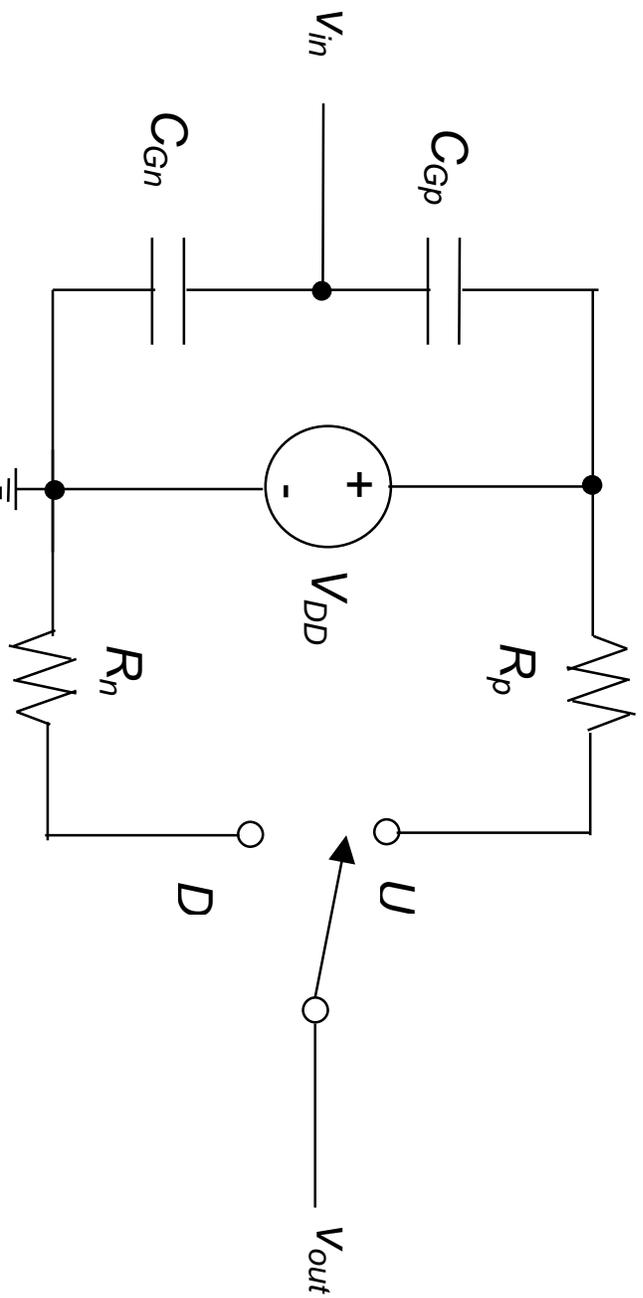
## First Order CMOS Inverter Model

The switches are “ganged” (move together) since they have the same trip voltages

**NMOS is closed when  $v_{in} > V_{Th}$ ; PMOS is open**

**PMOS is closed when  $v_{in} < V_{Th}$ ; NMOS is open**

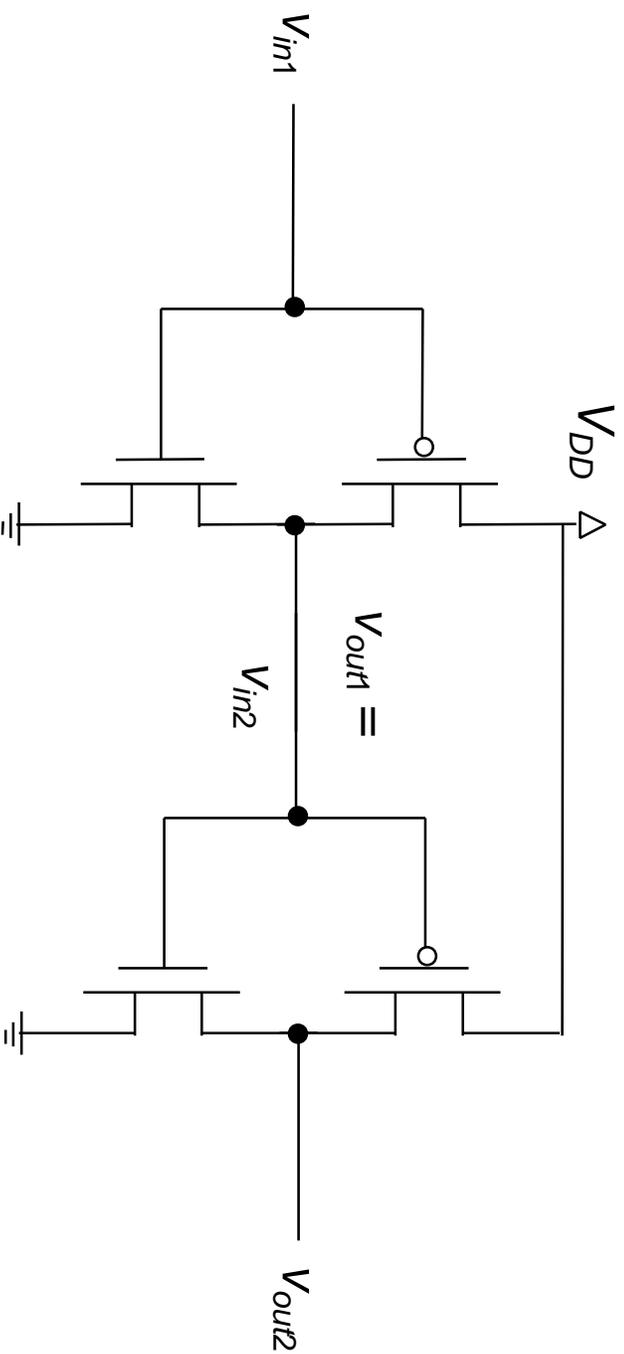
**Reduce to a single switch (Fig. 2.10, R&R)**



## “Cascaded” CMOS Inverters

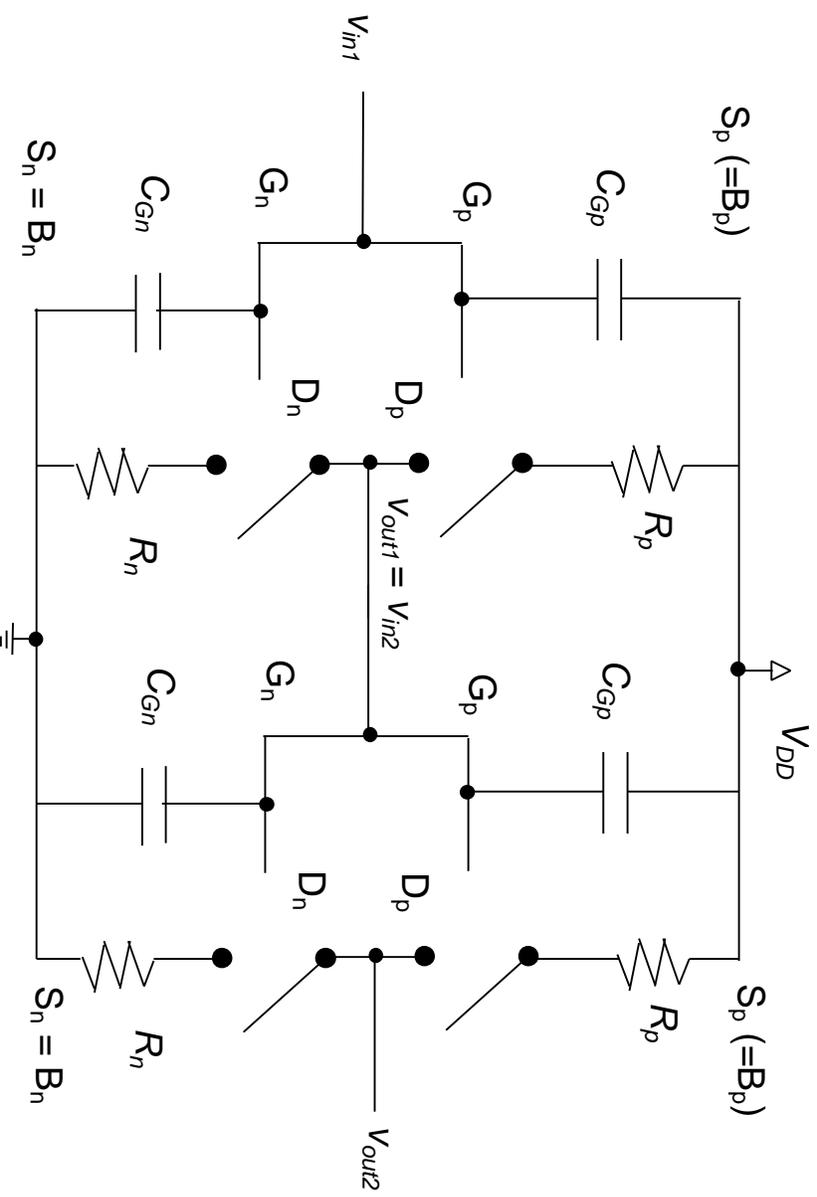
What’s connected to the  $V_{out}$  node?

Representative “load” ... possibly another CMOS inverter



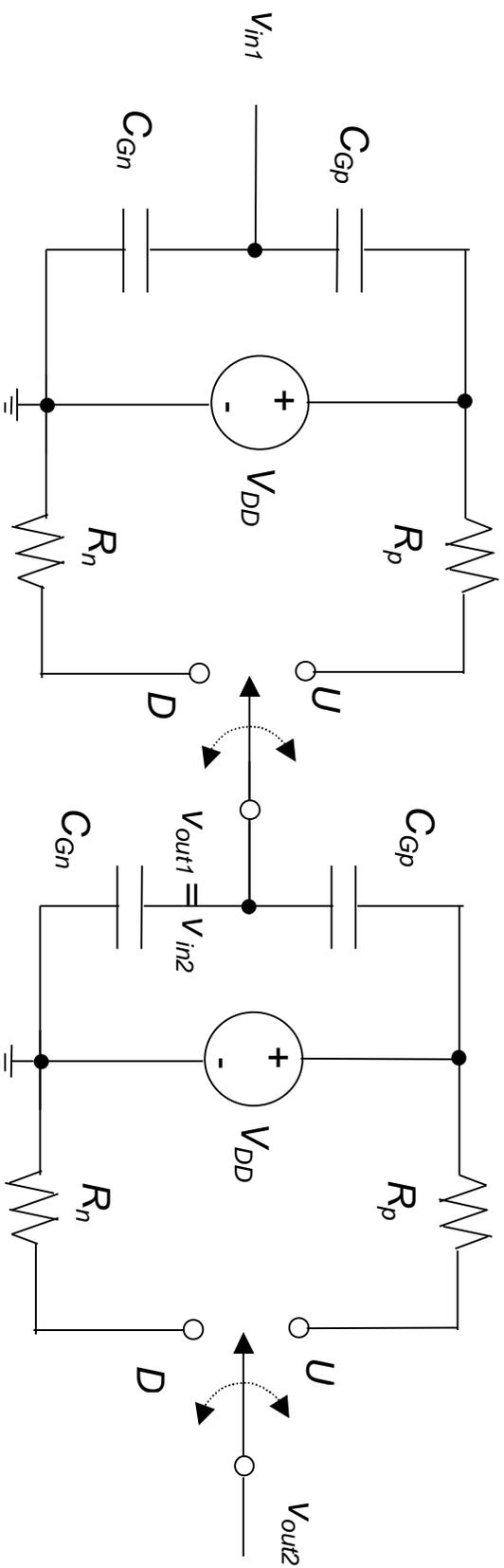
# Cascaded Identical CMOS Inverter Circuit Model

**Drain-bulk capacitances are omitted (at first), as is interconnect resistance and cap.**



## Simpler Representation

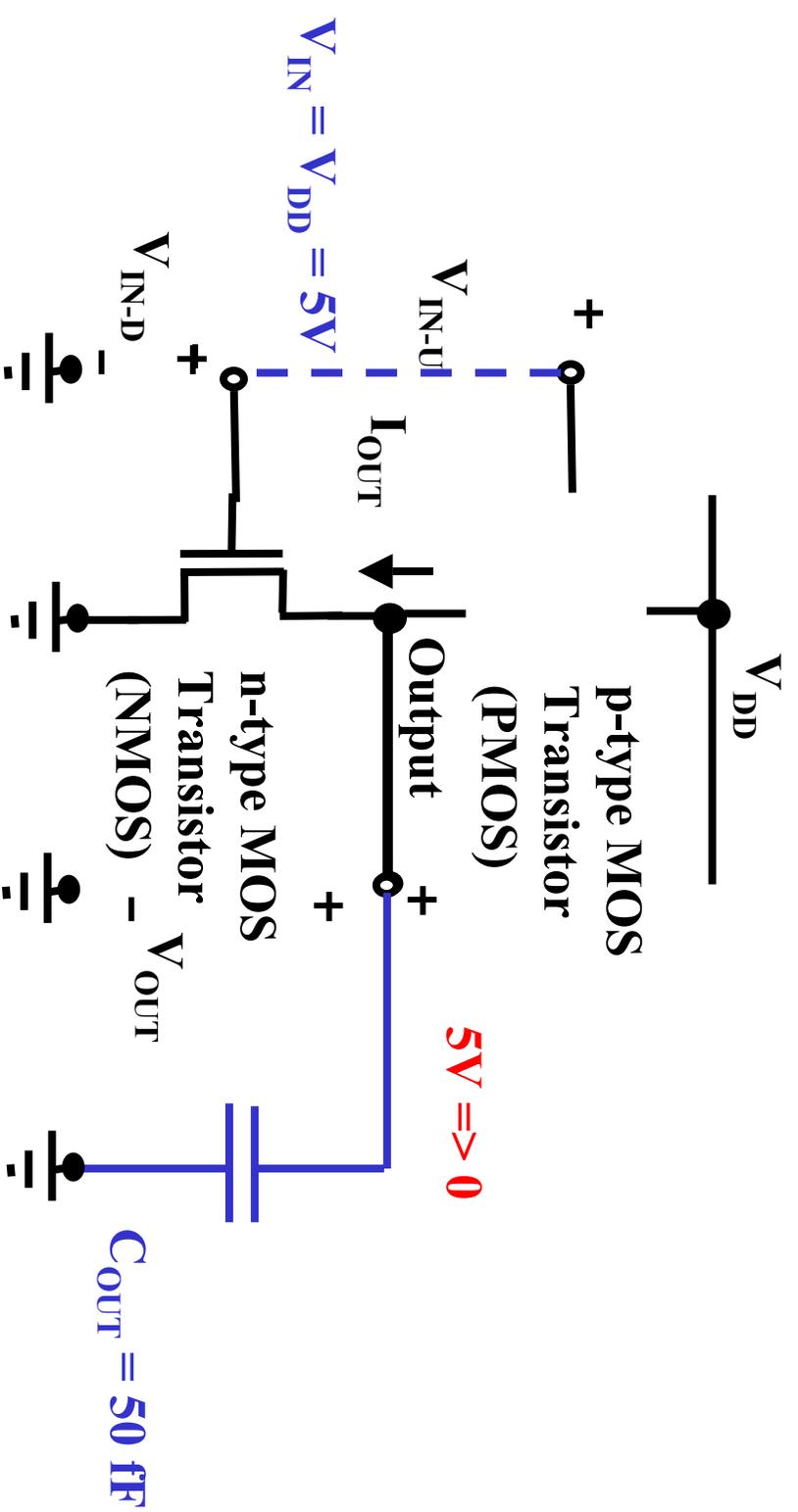
NMOS and PMOS transistors have the same logic thresholds, but operate in a complementary fashion  $\rightarrow$  reduce to a single switch per inverter



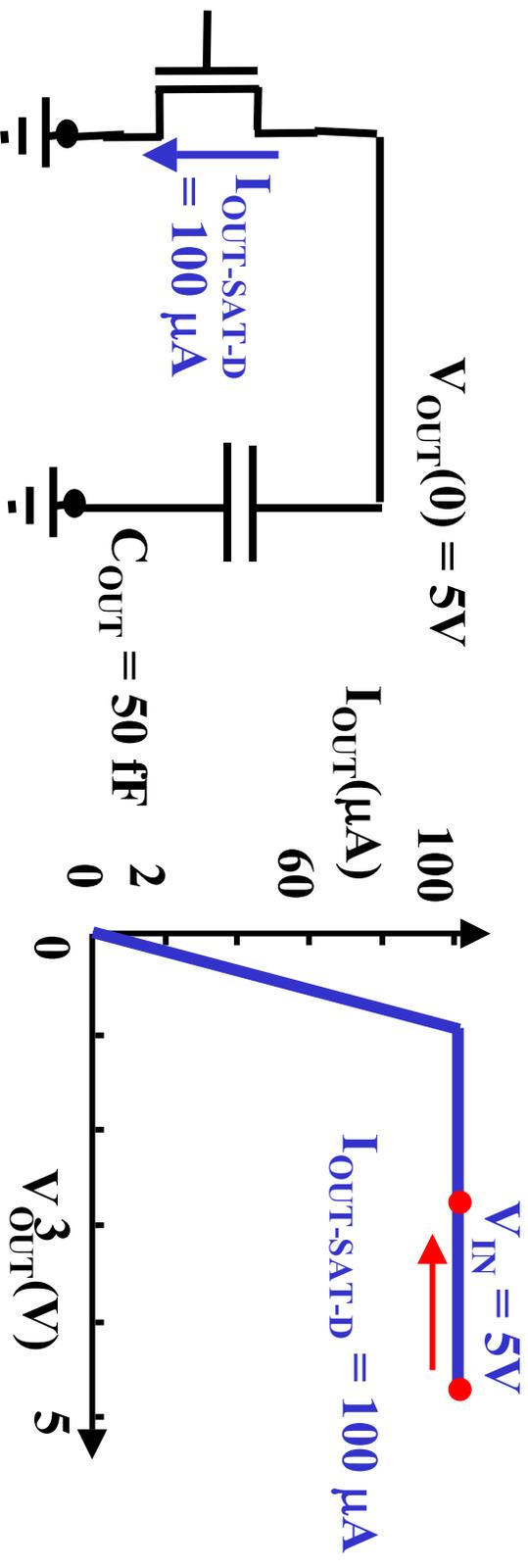
Transitions of interest:

1.  $V_{in1}$  increases above  $V_{Th}$  : switch for inverter 1 moves to “D” position from previous “U” position
2.  $V_{in1}$  decreases below  $V_{Tl}$  : switch for inverter 1 moves to “U” position from previous “D” position

# Transient Gate Problem: Discharging and Charging Capacitance on the Output



# Output Propagation Delay High to Low

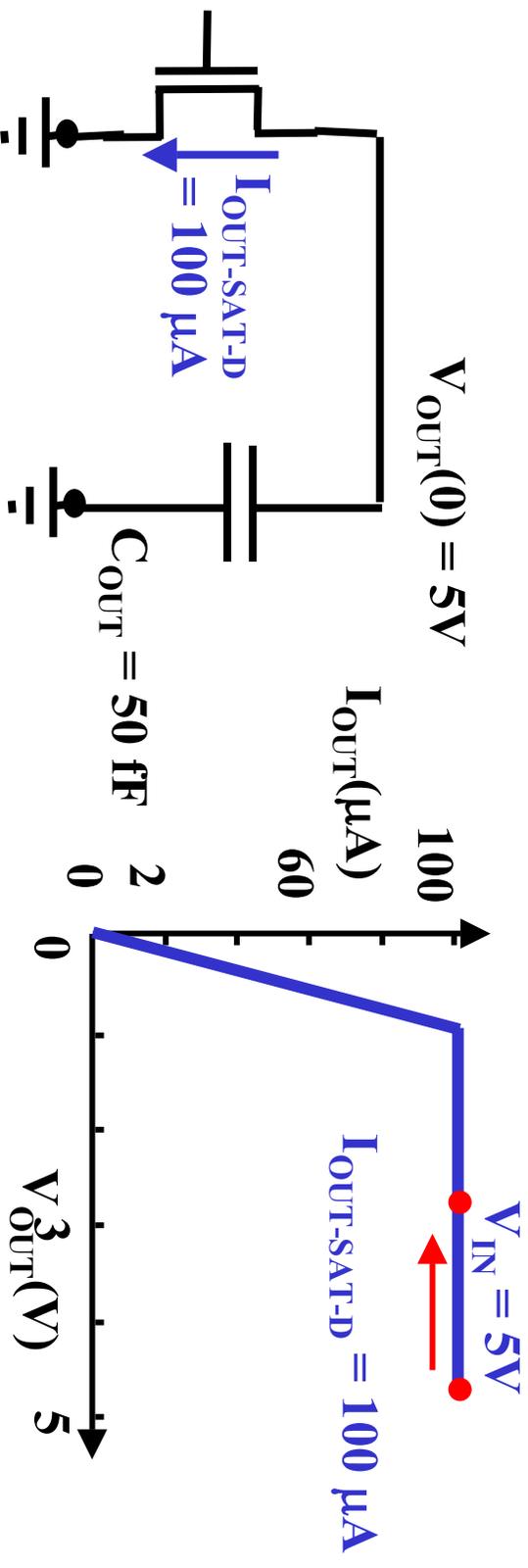


When  $V_{IN}$  goes High  $V_{OUT}$  starts decreases with time

Assume that the necessary voltage swing to cause the next downstream gate to begin to switch is  $V_{DD}/2$  or 2.5V.

That is the propagation delay  $\tau_{HL}$  for the output to go from high to low is the time to go from  $V_{DD} = 5\text{V}$  to to  $V_{DD}/2 = 2.5\text{V}$

# Output Propagation Delay High to Low (Cont.)



When  $V_{OUT} > V_{OUT-SAT-D}$  the available current is  $I_{OUT-SAT-D}$

For this circuit when  $V_{OUT} > V_{OUT-SAT-D}$  the available current is constant at  $I_{OUT-SAT-D}$  and the capacitor discharges.

The **propagation delay** is thus

$$\Delta t = \frac{C_{OUT} \Delta V}{I_{OUT-SAT-D}} = \frac{C_{OUT} V_{DD}}{2I_{OUT-SAT-D}} = \frac{50 \text{ fF} \cdot 2.5V}{100 \mu\text{A}} = 1.25 \text{ ns}$$

# Switched Equivalent Resistance Model

The above model assumes the device is an ideal constant current source.

- 1) This is not true below  $V_{OUT-SAT-D}$  and leads to in accuracies.
- 2) Combining ideal current sources in networks with series and parallel connections is problematic.

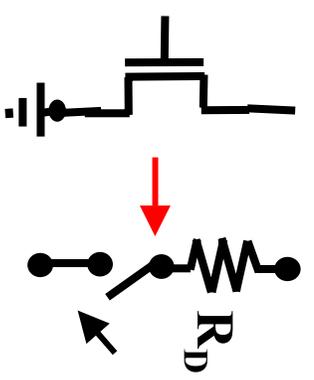
Instead define an equivalent resistance for the device by setting  $0.69R_D C_{OUT}$  equal to the  $\Delta t$  found above

This gives

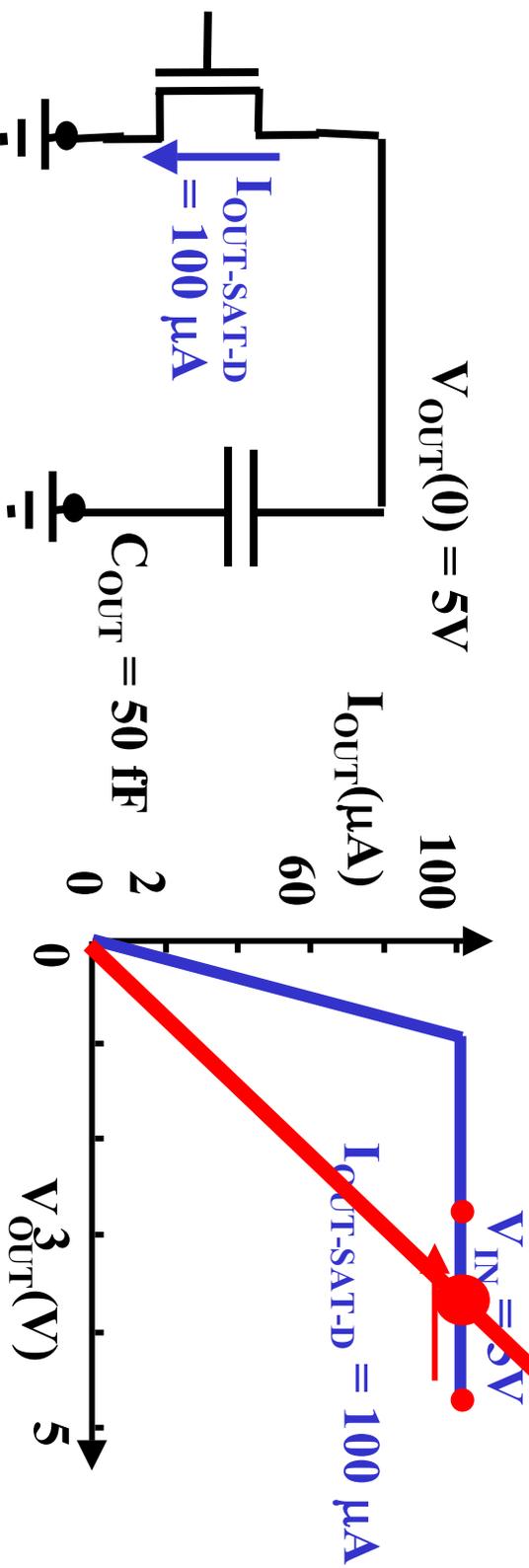
$$\Delta t = \frac{C_{OUT} V_{DD}}{2 I_{OUT-SAT-D}} = 0.69 R_D C_{OUT}$$

$$R_D = \frac{V_{DD}}{2 \cdot (0.69) I_{OUT-SAT-D}} \approx \frac{3}{4} \frac{V_{DD}}{I_{OUT-SAT-D}} = \frac{3}{4} \frac{5V}{100 \mu A} = 37.5 k\Omega$$

Each device can now be replaced by this equivalent resistor.



# $\frac{3}{4} V_{DD}/I_{SAT}$ Physical Interpretation



$\frac{3}{4} V_{DD}$  is the average value of  $V_{OUT}$

Approximate the NMOS device curve by a straight line from (0,0) to ( $I_{OUT-SAT-D}$ ,  $\frac{3}{4} V_{DD}$ ).

Interpret the straight line as a resistor with

$$1/(\text{slope}) = R = \frac{3}{4} V_{DD}/I_{SAT}$$

# Switched Equivalent Resistance Values

The resistor values depend on the properties of silicon, geometrical layout, design style and technology node.

n-type silicon has a carrier mobility that is 2 to 3 times higher than p-type.

The resistance is inversely proportion to the gate width/length in the geometrical layout.

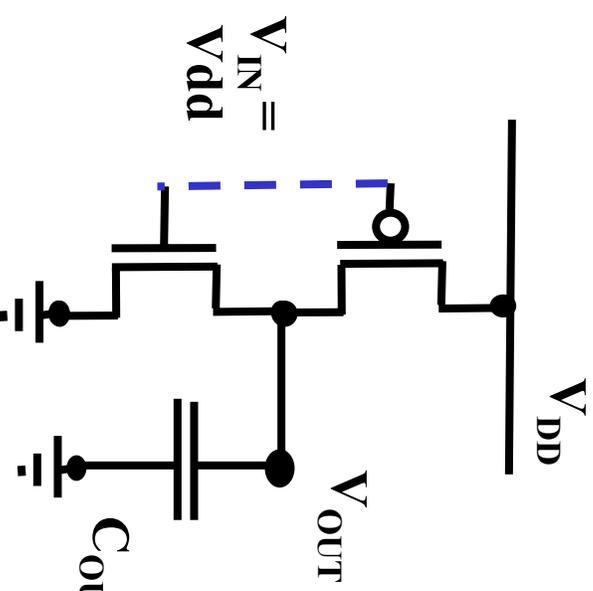
Design styles may restrict all NMOS and PMOS to be of a predetermined fixed size.

The current per unit width of the gate increases nearly inversely with the linewidth.

**For convenience in EE 42 we assume  $R_D = R_U = 10 \text{ k}\Omega$**

# Inverter Propagation Delay

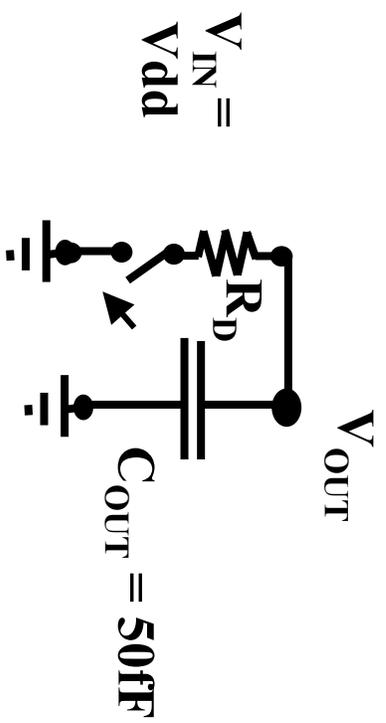
Discharge (pull-down)



$$\Delta t = 0.69R_D C_{OUT} = 0.69(10k\Omega)(50fF) = 345 \text{ ps}$$

Discharge (pull-up)

$$\Delta t = 0.69R_U C_{OUT} = 0.69(10k\Omega)(50fF) = 345 \text{ ps}$$



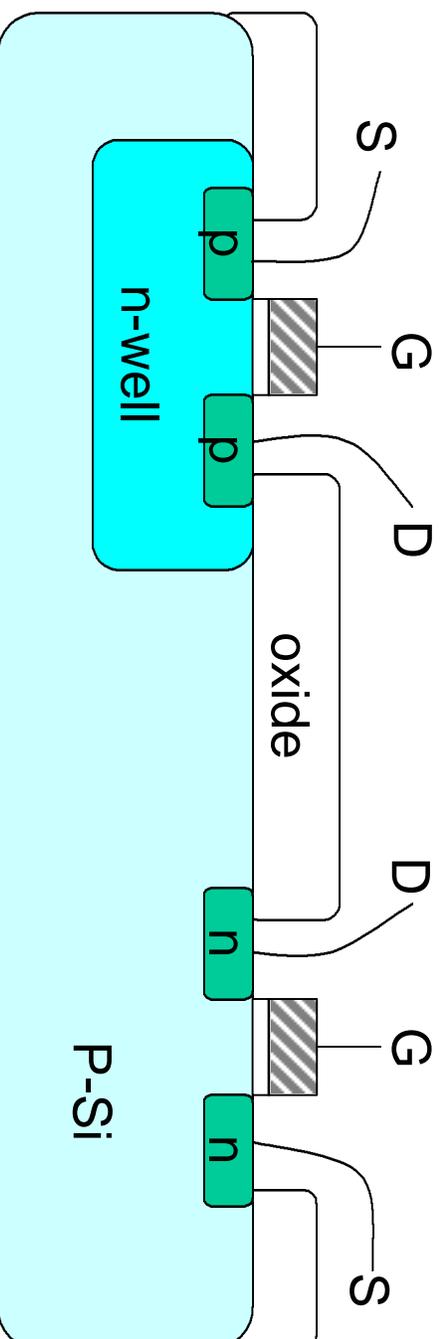
# CMOS

**Challenge: build both NMOS and PMOS on a single silicon chip**

**NMOS needs a p-type substrate**

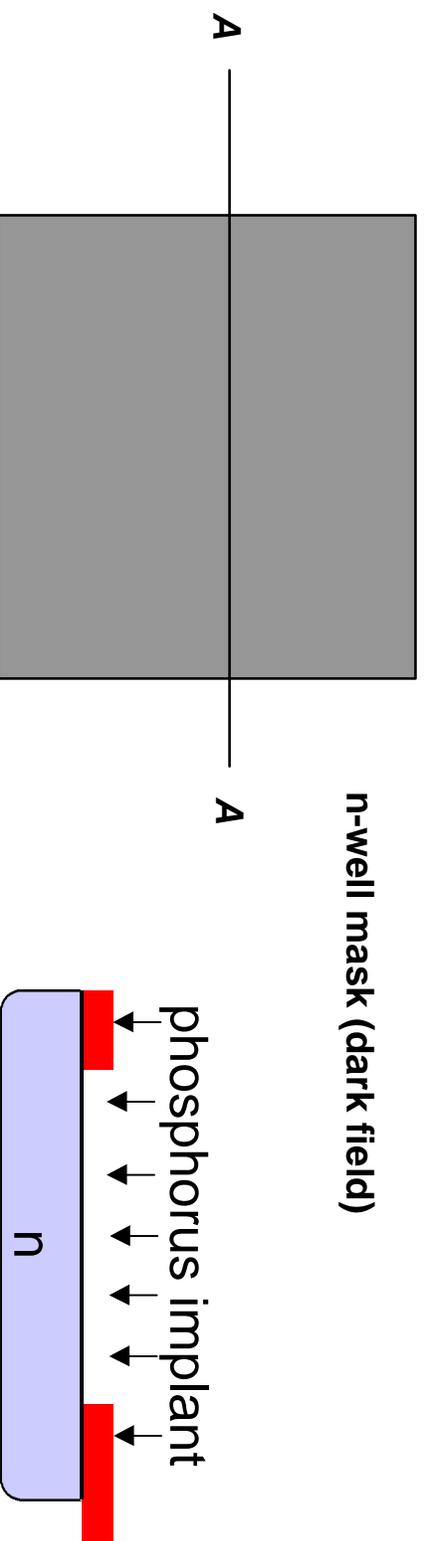
**PMOS needs an n-type substrate**

**Requires extra process steps**



## Additional Steps for CMOS

### Well Formation



### Process (before transistor fabrication)

- 1. start with p-type wafer; grow 250 nm oxide**
- 2. pattern oxide with n-well mask**
- 3. implant with phosphorus and anneal to form a 3  $\mu\text{m}$ -deep n-type region**

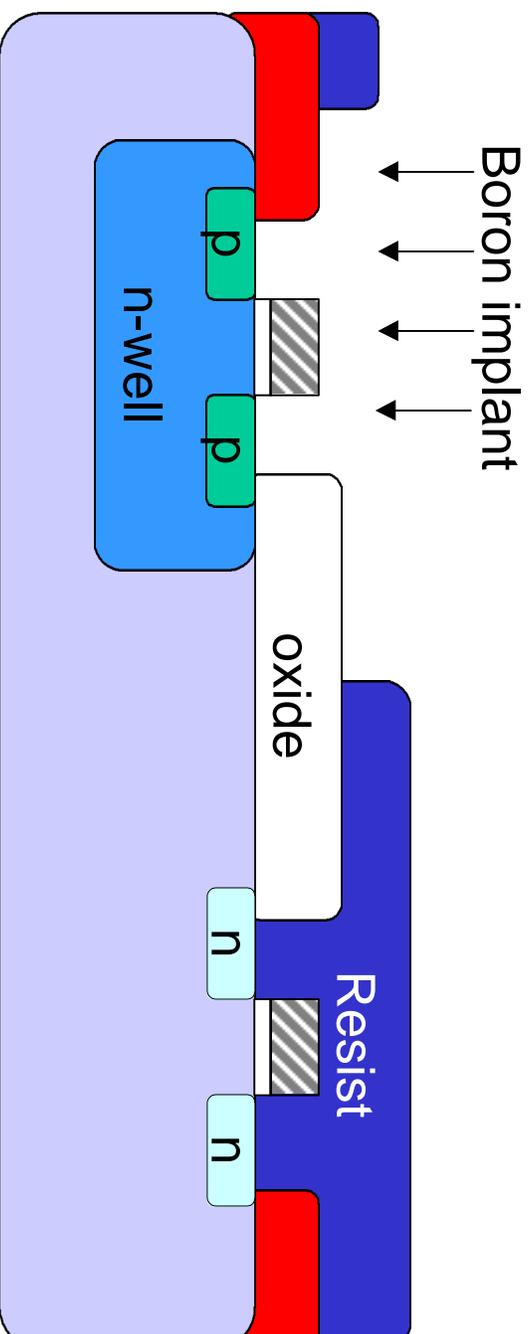
## FIRST ADDITIONAL COMPLICATION:

We must mask source-drain implants

“Select P-Channel” → We must protect n-channel device during boron implant **and**

“Select N-Channel” → We must protect p-channel device during As implant)

### Example: Select P ch



Moreover, it looks like reverse of the well mask, i.e., a “clearfield well mask” would work for the “select n-channel” mask.

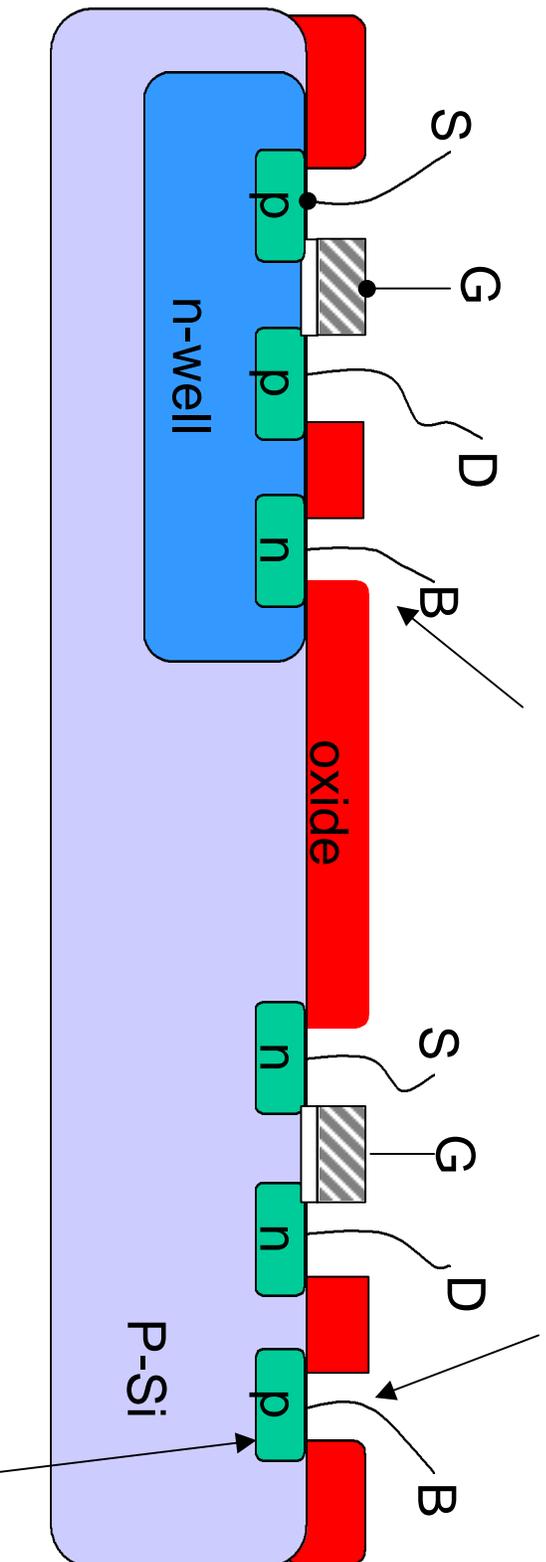
## AND ONE MORE COMPLICATION:

We need contacts to “body” or well and body of p-region

Easy to do – just modify “select” masks and oxide masks, i.e.,

- ① Create thin oxide spots for contact in original oxide mask, and
- ② Allow openings in select masks to dope these regions

Cut oxide here at first oxide mask.



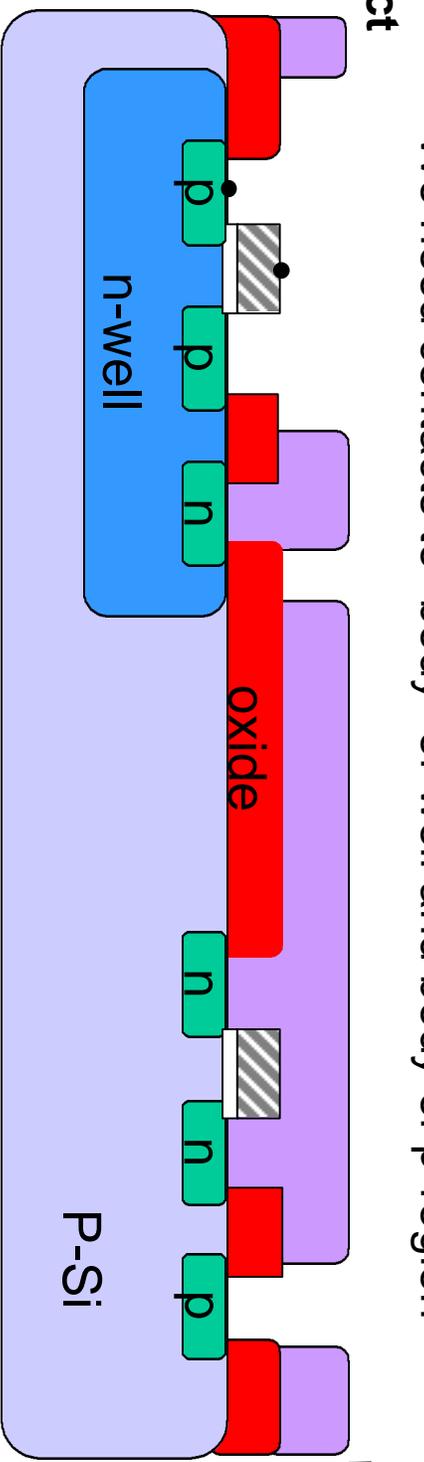
p implant area in substrate is to make electrical contact by Al wire easier

How to get n-regions implanted selectively with arsenic?

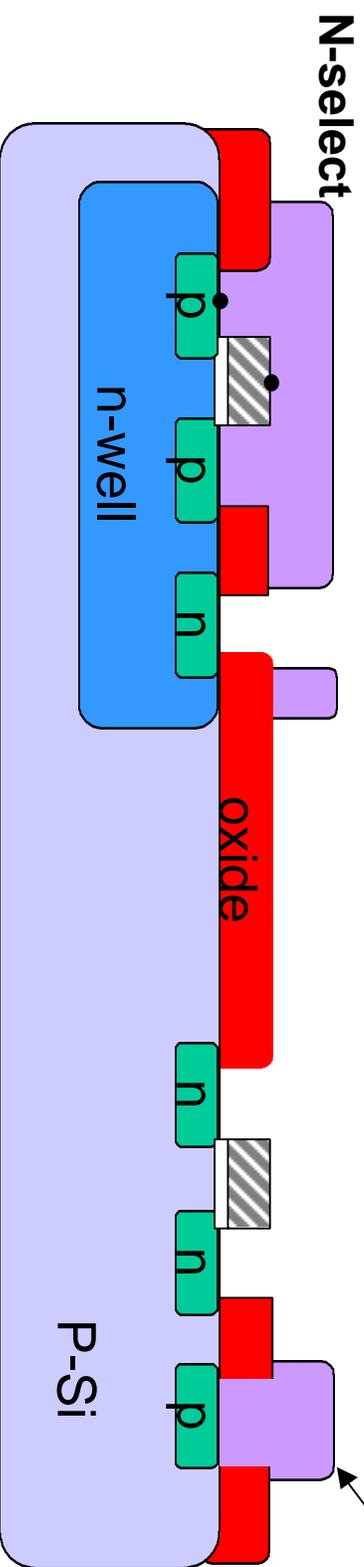
Could simply invert polarity of select mask at contacts.

# Cross-sections for Select Masks

We need contacts to "body" or well and body of p-region



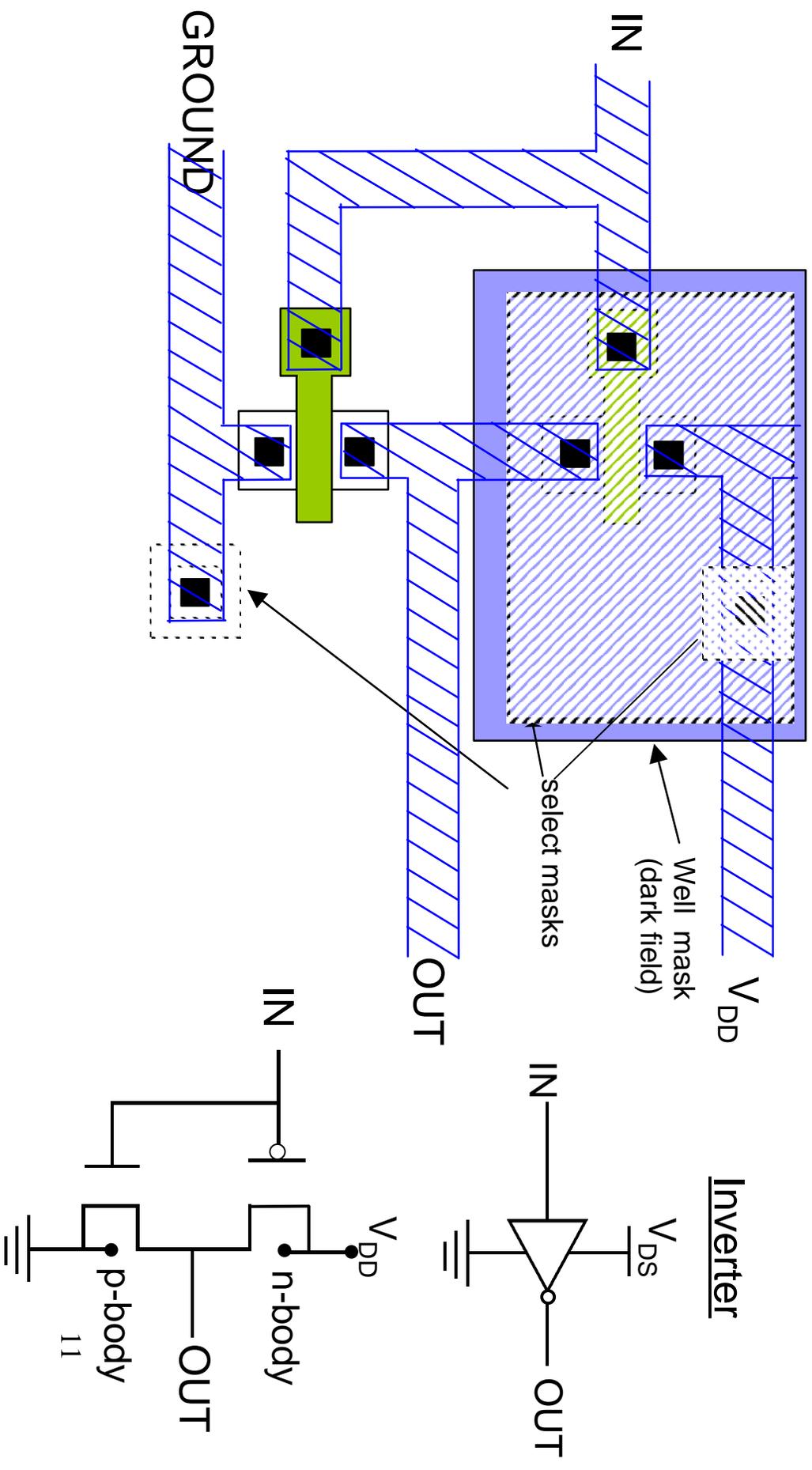
P-select is almost the same as well mask (except add p-Si contacts)



N-select is almost dark-field of well mask (except add n-Si contacts)

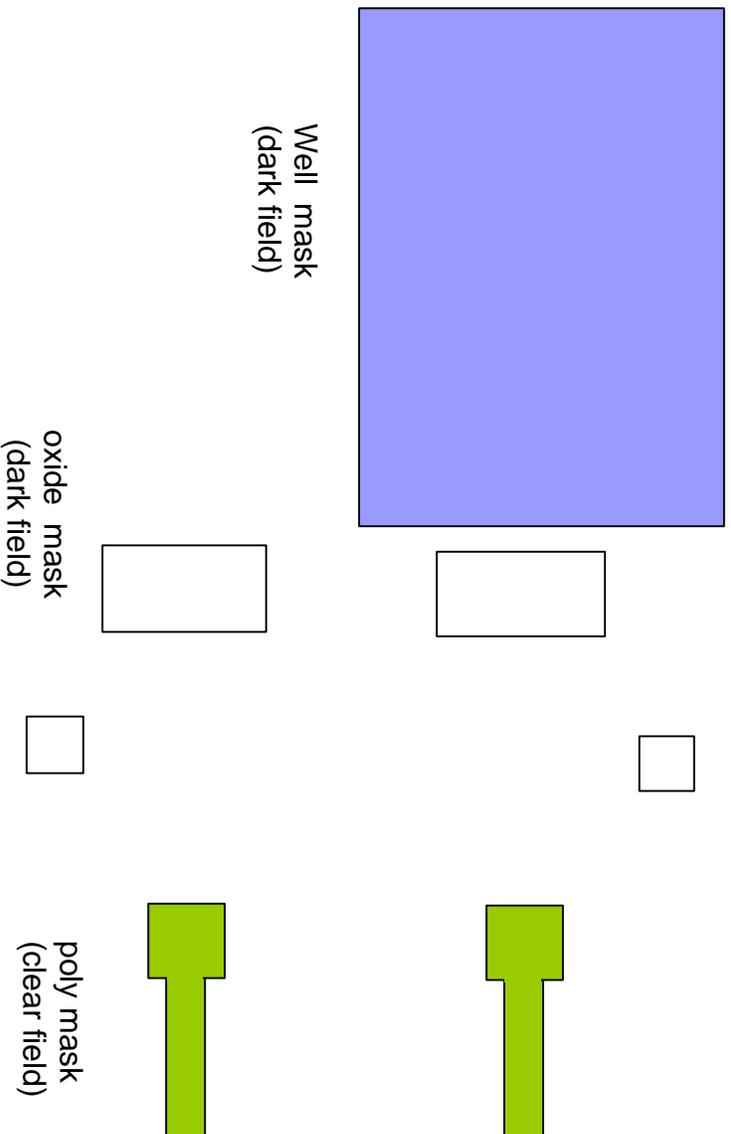
# Basic CMOS Process

## Well mask + select mask(s) + NMOS process



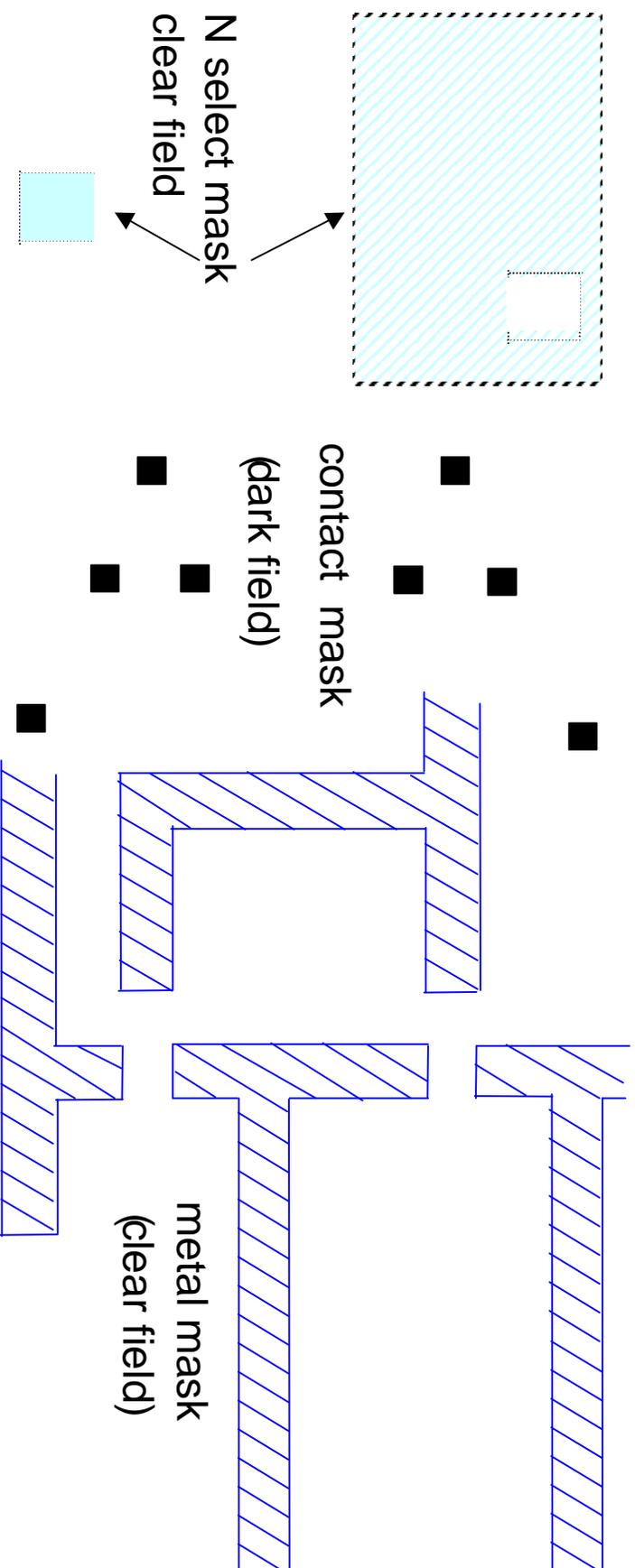
# Separate Masks

## Well, oxide, and polysilicon masks



# Separate Masks (cont.)

**Select masks, contact mask, and metal mask**



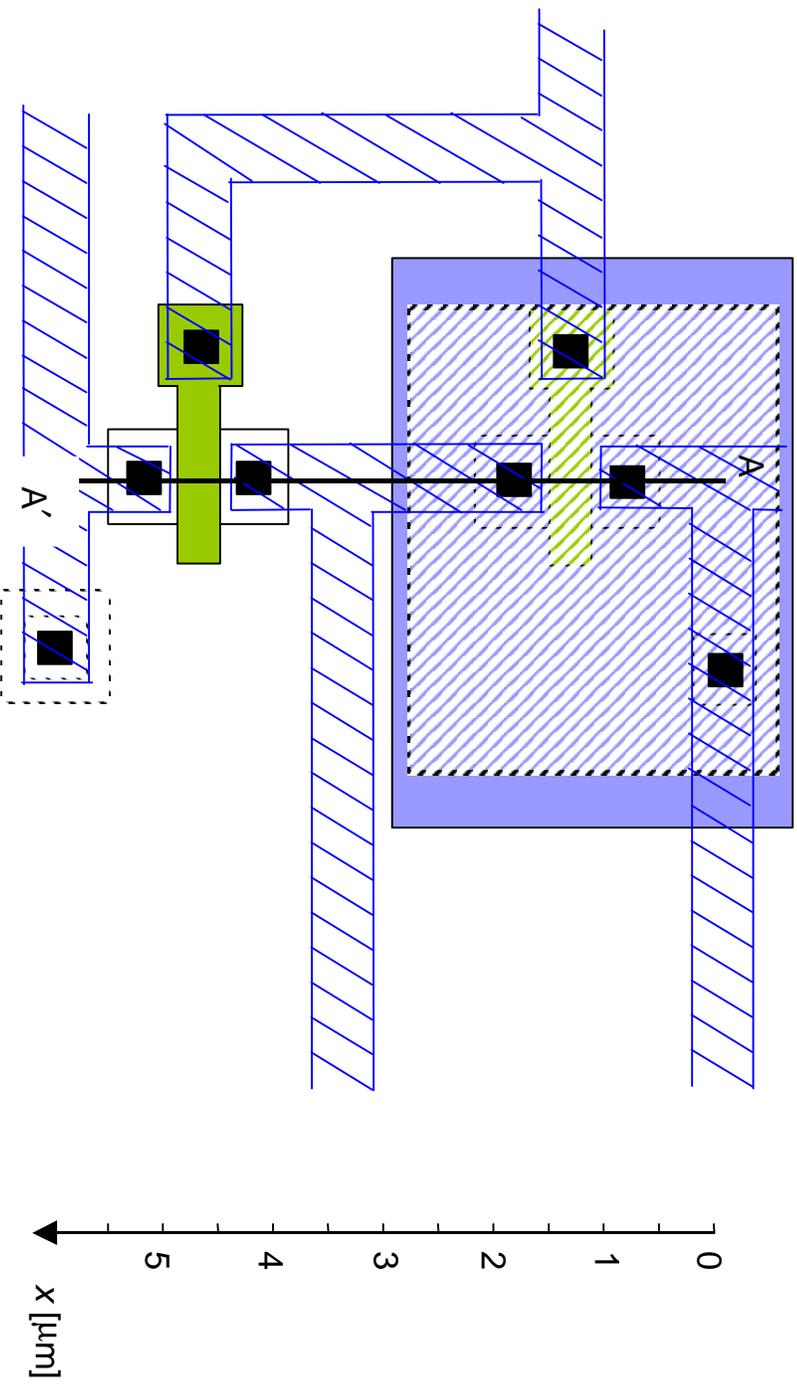
## CMOS Process Sequence

1. p-type starting material; grow 500 nm of oxide
  2. pattern oxide with well mask
  3. implant phosphorus and anneal (“well drive in”) to a depth of 3  $\mu\text{m}$
  4. strip off oxide
  5. grow 500 nm of oxide
  6. pattern with oxide mask
  7. grow 5 nm of oxide
  8. deposit 500 nm of n<sup>+</sup> polysilicon
  9. pattern with poly mask
  10. spin on resist
  11. pattern with the select mask (dark field)
  12. implant boron; strip off resist
  13. spin on resist
  14. pattern with the select mask (clear field)
- Same pattern except for well and substrate contacts

## **CMOS Process Sequence (cont.)**

- 15. implant arsenic; strip off resist and anneal implants to form source and drain regions**
- 16. deposit 500 nm of oxide**
- 17. pattern using contact mask (dark field)**
- 18. deposit 1  $\mu\text{m}$  of aluminum**
- 19. pattern using metal mask (clear field)**

# CMOS Cross Sections



## Conclusion

- Completed our propagation delay model
- Switch-RC model of the CMOS inverter
- $T_{LH}$  and  $T_{HL}$  calculations
- CMOS layouts and fabrication steps
- References: Lectures 18 and 19 (Fall 1999) and Lecture 21 (Spring 2003)

**Next time...**

- Barring unforeseen circumstances: GUEST LECTURE BY PROF. TSU JAE-KING
- HW #5 due!
- START PREPARING FOR MIDTERM!